



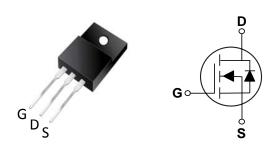
#### **General Description**

The I2MNAB850 is a high voltage power MOSFET designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristic.

This power MOSFET is usually used in high speed switching applications of switching power supplies and adaptors.

BV <sub>DSS</sub>	R <sub>DS(ON)</sub>	$I_D$
650 V	0.85 Ω	12 A

#### TO-220F Pin Configuration



### **Features**

- $R_{DS(ON)} \le 0.85 \Omega @V_{GS} = 10V$
- · Fast switching capability
- · Avalanche energy tested
- · Improved dv/dt capability

Symbol	Parameter	Rating	Unit
$V_{DS}$	Drain-Source Voltage	650	V
$V_{GS}$	Gate-Source Voltage	±30	V
I <sub>D</sub>	Drain Current - Continuous	12	Α
I <sub>DM</sub>	Drain Current - Pulsed (NOTE 2)	24	А
E <sub>AS</sub>	Single Pulse Avalanche Energy (NOTE 3)	576	m
$P_{D}$	Power Dissipation	40	W
T <sub>J</sub>	Operating Junction Temperature Range	-50 to 150	°C
T <sub>STG</sub>	Storage Temperature Range	-50 to 150	°C
larking Code		NAB850	

#### NOTES:

- Absolute maximum ratings are those values beyond which the device could be permanently damaged.
  Absolute maximum ratings are stress ratings only and functional device operation is not implied.
- ${\bf 2.} \ {\bf Repetitive} \ {\bf Rating:} \ {\bf Pulse} \ {\bf width} \ {\bf limited} \ {\bf by} \ {\bf maximum} \ {\bf junction} \ {\bf temperature}.$
- 3. L=30mH, I<sub>AS</sub>=6.2A, V<sub>DD</sub>=50V, R<sub>G</sub>=25 $\Omega$ , Starting T<sub>J</sub>= 25°C

Thermal Characteristics					
Symbol	Symbol Parameter			Unit	
$R_{\theta JA}$	Thermal Resistance Junction to Ambient		62.5	°C/W	
$R_{ heta JC}$	Thermal Resistance Junction to Case		3.1	°C/W	





### Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

#### **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS}$ =0V , $I_D$ =250uA	650			٧
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =650V , V <sub>GS</sub> =0V			10	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}$ =±30V , $V_{DS}$ =0V			±100	nA

#### On Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS}$ =10V , $I_{D}$ =6A			0.85	Ω
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}$ , $I_D=250uA$	2.0		4.0	V

#### **Dynamic and switching Characteristics (NOTE3)**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
$Q_g$	Total Gate Charge	$V_{DS}$ =520V , $V_{GS}$ =10V , $I_{D}$ =12A ,		36		
$Q_{gs}$	Gate-Source Charge	I <sub>G</sub> =1mA		8.6		nC
$Q_{gd}$	Gate-Drain Charge	(NOTE 4 \ 5)		10		
$T_{d(on)}$	Turn-On Delay Time	V 400V V 40V D 050		22		
$T_r$	Rise Time	$V_{DS}$ =100V , $V_{GS}$ =10V , $R_{G}$ =25 $\Omega$ , $I_{D}$ =12A		23		nS
$T_{d(off)}$	Turn-Off Delay Time	(NOTE 4 \ 5)		115		110
T <sub>f</sub>	Fall Time	(1012 : 3)		32		
C <sub>iss</sub>	Input Capacitance			1540		
C <sub>oss</sub>	Output Capacitance	$V_{DS}$ =25V , $V_{GS}$ =0V , f=1MHz		150		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			12		

### **Drain-Source Diode Characteristics and Ratings**

	<u> </u>					
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
I <sub>S</sub>	Maximum Body-Diode Continuous Current				12	Α
I <sub>SM</sub>	Maximum Body-Diode Pulsed Current				24	Α
$V_{SD}$	Diode Forward Voltage (NOTE 4)	V <sub>GS</sub> =0V , I <sub>S</sub> =12A			1.4	V
trr	Reverse Recovery Time	I <sub>S</sub> =12A , V <sub>GS</sub> =0V ,		470		nS
Qrr	Reverse Recovery Charge	di/dt=100A/µs		12		uC

## NOTES:

- 4. Pulse test : pulse width  $\leq$  300us , duty cycle  $\leq$  2%.
- $5. \ Essentially \ independent \ of \ operating \ temperature.$





### **Test Circuits And Waveforms**

FIG. 1-Peak Diode Recovery dv/dt Test Circuit

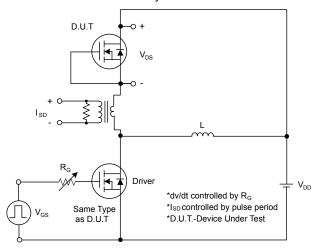


FIG. 2-Peak Diode Recovery dv/dt Waveforms

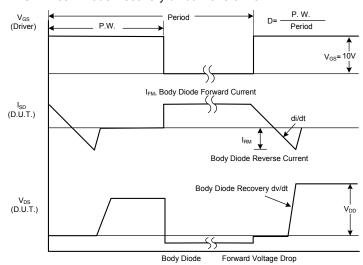


FIG. 3-Switching Test Circuit

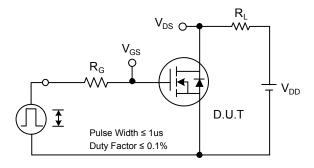


FIG. 4-Switching Waveforms

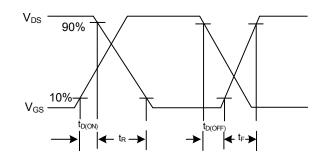


FIG. 5-Gate Charge Test Circuit

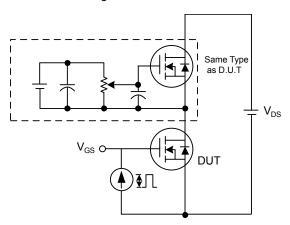
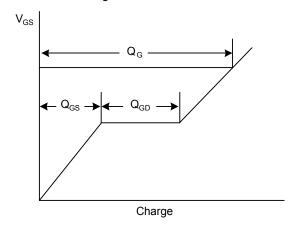


FIG. 6-Gate Charge Waveform







### **Test Circuits And Waveforms**

FIG. 7-Unclamped Inductive Switching Test Circuit

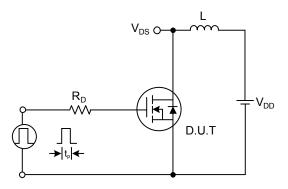
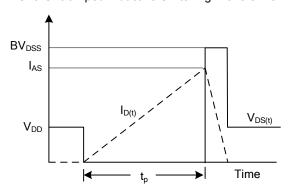
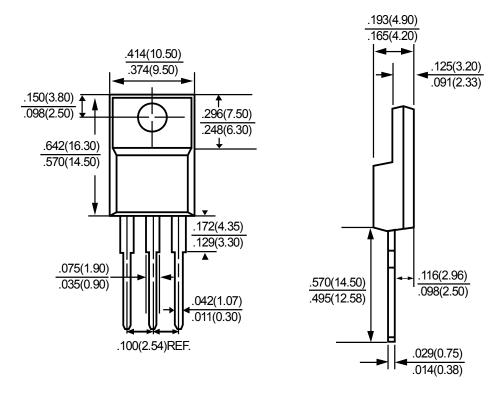


FIG. 8-Unclamped Inductive Switching Waveforms



### **Package Outline Dimensions**



**TO-220F**Dimensions in inches and (millimeters)





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